

| | Search Terms |
|----|--------------|
| 1 | ALTER |
| 2 | ALTERED |
| 3 | ALTEREDS |
| 4 | ALTERING |
| 5 | ALTERINGS |
| 6 | ALTERS |
| 7 | AREA |
| 8 | AREAS |
| 9 | CHANGE |
| 10 | CHANGED |
| 11 | CHANGEDS |
| 12 | CHANGES |
| 13 | CHANGING |
| 14 | CHANGINGS |
| 15 | CIRCUIT |
| 16 | CIRCUITS |
| 17 | FAIL |
| 18 | FAILED |
| 19 | FAILED |
| 20 | FAILING |
| 21 | FAILINGS |
| 22 | FAILS |
| 23 | FAILURE |
| 24 | FAILURES |
| 25 | FAULT |
| 26 | FAULTIES |
| 27 | FAULTS |
| 28 | FAULTY |
| 29 | FAULTYS |
| 30 | LOGIC |
| 31 | LOGICS |
| 32 | NUMBER |
| 33 | NUMBERS |

| | Total | US-PGPUB | USPAT | USOCR | EPO | JPO | Derwent | IBM TDB |
|----|---------|----------|-------|-------|-----|-----|---------|---------|
| 1 | 349423 | | | | | | | |
| 2 | 351636 | | | | | | | |
| 3 | 0 | | | | | | | |
| 4 | 231046 | | | | | | | |
| 5 | 10 | | | | | | | |
| 6 | 79524 | | | | | | | |
| 7 | 3398267 | | | | | | | |
| 8 | 1264538 | | | | | | | |
| 9 | 2479088 | | | | | | | |
| 10 | 1222329 | | | | | | | |
| 11 | 7 | | | | | | | |
| 12 | 2575404 | | | | | | | |
| 13 | 1202101 | | | | | | | |
| 14 | 194 | | | | | | | |
| 15 | 3947741 | | | | | | | |
| 16 | 1195854 | | | | | | | |
| 17 | 315466 | | | | | | | |
| 18 | 161192 | | | | | | | |
| 19 | 0 | | | | | | | |
| 20 | 60466 | | | | | | | |
| 21 | 1287 | | | | | | | |
| 22 | 216095 | | | | | | | |
| 23 | 623505 | | | | | | | |
| 24 | 95205 | | | | | | | |
| 25 | 201665 | | | | | | | |
| 26 | 4 | | | | | | | |
| 27 | 76046 | | | | | | | |
| 28 | 80081 | | | | | | | |
| 29 | 0 | | | | | | | |
| 30 | 566270 | | | | | | | |
| 31 | 5118 | | | | | | | |
| 32 | 4938000 | | | | | | | |
| 33 | 1208613 | | | | | | | |

| | Search Terms |
|----|--|
| 34 | TESTCASE |
| 35 | TESTCASES |
| 36 | ((((TESTCASE SAME (FAILING OR FAULTY OR FAILED OR FAIL OR FAULT OR FAILURE)) AND ((LOGIC SAME AREA) SAME (ALTERING OR ALTER OR ALTERED OR CHANGED OR CHANGING OR CHANGE) SAME CIRCUIT)) AND (LOGIC SAME AREA SAME NUMBER)) |

| | Total | US-PGPUB | USPAT | USOCR | EPO | JPO | Derwent | IBM TDB |
|----|-------|----------|-------|-------|-----|-----|---------|---------|
| 34 | 234 | | | | | | | |
| 35 | 169 | | | | | | | |
| 36 | 0 | | | | | | | |

| | Search Terms |
|----|---|
| 1 | ALTER |
| 2 | ALTERED |
| 3 | ALTEREDS |
| 4 | ALTERING |
| 5 | ALTERINGS |
| 6 | ALTERS |
| 7 | LOGIC |
| 8 | LOGICS |
| 9 | NORMAN-JASON |
| 10 | NORMAN-JASONS |
| 11 | PRATT-NANCIES |
| 12 | PRATT-NANCY |
| 13 | PRATT-NANCYS |
| 14 | RO |
| 15 | ROE |
| 16 | ROES |
| 17 | ROS |
| 18 | TESTCASE |
| 19 | TESTCASES |
| 20 | VENTRONE-SEBASTIAN |
| 21 | VENTRONE-SEBASTIANS |
| 22 | (((((NORMAN-JASON.IN.) OR (PRATT-NANCY.IN.)) OR (VENTRONE-SEBASTIAN.IN.)) AND TESTCASE) AND (ALTERING OR ALTER OR ALTERED OR RO) AND LOGIC) |

| | Total | US-PGPUB | USPAT | USOCR | EPO | JPO | Derwent | IBM TDB |
|----|---------|----------|-------|-------|-----|-----|---------|---------|
| 1 | 349423 | | | | | | | |
| 2 | 351636 | | | | | | | |
| 3 | 0 | | | | | | | |
| 4 | 231046 | | | | | | | |
| 5 | 10 | | | | | | | |
| 6 | 79524 | | | | | | | |
| 7 | 566270 | | | | | | | |
| 8 | 5118 | | | | | | | |
| 9 | 0 | | | | | | | |
| 10 | 0 | | | | | | | |
| 11 | 0 | | | | | | | |
| 12 | 0 | | | | | | | |
| 13 | 0 | | | | | | | |
| 14 | 1560107 | | | | | | | |
| 15 | 26701 | | | | | | | |
| 16 | 1829 | | | | | | | |
| 17 | 15244 | | | | | | | |
| 18 | 234 | | | | | | | |
| 19 | 169 | | | | | | | |
| 20 | 6 | | | | | | | |
| 21 | 0 | | | | | | | |
| 22 | 0 | | | | | | | |

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Example: optical <and> (fiber <or> fibre) <in> ti
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(testcase<or>testcases) <and>
(logic<paragraph>areas<paragraph>number) <and> circuit

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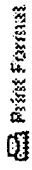
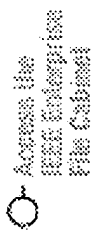
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